microPRO[™] RTP

Selective Laser Annealing System for Semiconductor Applications

The microPRO[™] RTP, a new laser annealing system designed to enable several key process steps in semiconductor, power device and MEMS manufacturing, combines a state-of-the-art laser optic module with 3D-Micromac's modular semiconductor wafer manufacturing platform. It provides selective annealing with high repeatability and throughput in a versatile system.

The microPRO[™] RTP features a line scan option for vertical selective annealing and a step-and-repeat spot option for horizontal selective annealing, as well as three optional laser wavelengths. The microPRO[™] RTP addresses a variety of applications, including:

- Giant magneto resistive (GMR) and tunneling magneto
 resistive (TMR) sensor manufacturing
- Ohmic contact formation in silicon carbide (SiC) power devices to improve resistance
- Dopant activation for insulated gate bipolar transistors (IGBTs), as well as activation of backside illuminated (BSI)
 CMOS image sensors and amorphous silicon (a-Si)







The microPRO[™] RTP provides numerous advantages compared to existing annealing methods, including:

- High precision and repeatability in both X and Y directions
- High selectivity to different substrates and films, with multiple options for laser pulse length, energy and overlap to ensure no damage to the area surrounding the target site
- Very high energy homogeneity
- Precise process monitoring
- Flexibility to handle substrate diameters ranging from 50 mm up to 300 mm

	microPRO [™] RTP for Giant Magneto Resistive (GMR) and Tunneling Magneto Resistive (TMR) Sensor Manufacturing	microPRO™ RTP for Ohmic Contact Formation (OCF) in Silicon Carbide (SiC) Power Devices
Wafer size	• Up to 300 mm (12") wafer size	Up to 150 mm (6") wafer size
Laser source	 NIR Laser for GMR/TMR sensor formation Integrated laser power monitoring Dimension of exposure area controlled by recipe 	 ns laser source Wavelength: 355 nm Integrated process monitoring
Magnet unit	 Recipe based programming of: Magnetic field strength Orientation of magnetic field 	• Not available
Positioning system	 High precision X/Y/Z stage Rotation axis with vacuum chuck X/Y accuracy: < 8 μm 	 High precision X/Y/Z stage Rotation axis with vacuum chuck X/Y accuracy: < 8 µm
Wafer chuck	 Vacuum hot chuck with lift pins (up to 200°C) Temperature homogeneity ± 2°C 	Vacuum chuck
Options	 Fully automated open cassette wafer handling Wafer pre-aligner ID reader for wafer and/or cassette SEGS/GEM implementation Fan filter unit 	 Inert gas chamber Full-wafer exposure Fully automated open cassette wafer handling ID Reader for wafer and/or cassette SECS/GEM implementation Fan filter unit
Software microMMI	 Control of all components and parameters Different user levels supported (administrator, supervisor, operator) Interface for fab integration (SECS/GEM) 	 Control of all components and parameters Different user levels supported (administrator, supervisor, operator) Interface for fab integration (SECS/GEM)
Standards	 Compatible with common SEMI standards Laser safety class 1 Clean room class ISO 5 	 Compatible with common SEMI standards Laser safety class 1 Clean room class ISO 5
Consumables	Cooling water, compressed air, electrical power, vacuum	 Cooling water, compressed air, electrical power, vacuum
Machine dimensions	 2716 x 1642 x 2308 mm³ (W x D x H) 	 2000 x 1629 x 2155 mm³ (W x D x H), w/o load port

Changes in accordance to technical progress are reserved.

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